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Fault-Tolerance Techniques for Spacecraft Control Computers
Mengfei Yang, Gengxin Hua, Yanjun Feng, Jian Gong

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**DESCRIPTION**

Comprehensive coverage of all aspects of space application oriented fault tolerance techniques

- Experienced expert author working on fault tolerance for Chinese space program for almost three decades
- Initiatively provides a systematic texts for the cutting-edge fault tolerance techniques in spacecraft control computer, with emphasis on practical engineering knowledge
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- Beneficial to readers inside and outside the area of space applications

**ABOUT THE AUTHOR**

Dr. Yang Mengfei, Professor, Chief Engineer and Chief Commander of China Academy of Space Technology, Beijing, China. Professor Yang Mengfei received his Master's degree in computer application from Beijing Institute of Control Engineering, China Academy of Space Technology in 1985. He then devoted himself to the research of fault tolerance computing, control of computer technology for space applications, and high-dependable software. In 2005, he received Ph.D. degree from Tsinghua University. Professor Yang has received numerous awards for his outstanding work and contribution to this sector.
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